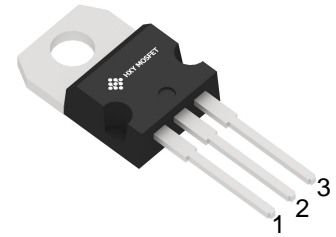




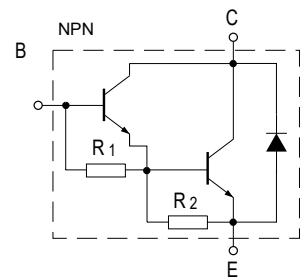
## Features

- Monolithic Darlington configuration
- Integrated antiparallel collector-emitter diode



TO-220S

1.BASE  
2.COLLECTOR  
3.EMITTER



R1 typ. =5 K R2 typ. =210

## Maximum Ratings (Ta=25 unless otherwise noted)

Symbol	Parameter	Value	Unit
$V_{CBO}$	Collector-base voltage ( $I_E = 0$ )	100	V
$V_{CEO}$	Collector-emitter voltage ( $I_B = 0$ )	100	V
$V_{EBO}$	Emitter-base voltage ( $I_C = 0$ )	5	V
$I_C$	Collector current	10	A
$I_{CM}$	Collector peak current	20	A
$I_B$	Base current	0.5	A
$P_{TOT}$	Total dissipation at $T_{case} = 25^\circ\text{C}$	90	W
$T_{STG}$	Storage temperature	-65 to 150	$^\circ\text{C}$
$T_J$	Max. operating junction temperature	150	$^\circ\text{C}$

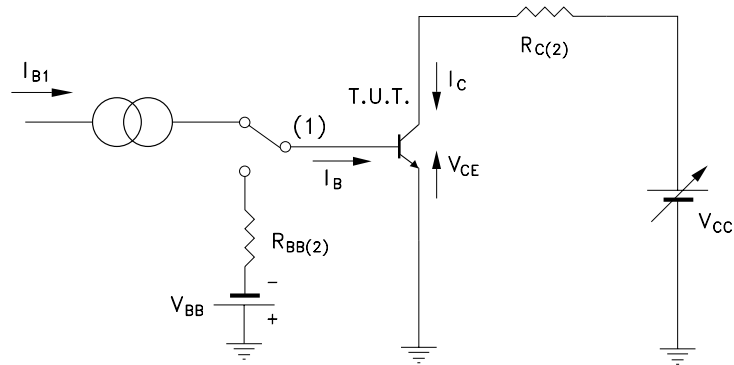
## Electrical Characteristics (Ta=25 unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{CBO}$	Collector cut-off current ( $I_E = 0$ )	$V_{CB} = 100\text{ V}$			1	mA
$I_{CEO}$	Collector cut-off current ( $I_B = 0$ )	$V_{CE} = 50\text{ V}$			2	mA
$I_{EBO}$	Emitter cut-off current ( $I_C = 0$ )	$V_{EB} = 5\text{ V}$			2	mA
$V_{CEO(sus)}^{(1)}$	Collector-emitter sustaining voltage ( $I_B = 0$ )	$I_C = 30\text{ mA}$	100			V
$V_{CE(sat)}^{(1)}$	Collector-emitter saturation voltage	$I_C = 5\text{ A}$ $I_B = 10\text{ mA}$ $I_C = 10\text{ A}$ $I_B = 40\text{ mA}$			2 3	V V
$V_{BE(on)}^{(1)}$	Base-emitter on voltage	$I_C = 10\text{ A}$ $V_{CE} = 4\text{ V}$			3	V
$h_{FE}^{(1)}$	DC current gain	$I_C = 5\text{ A}$ $V_{CE} = 4\text{ V}$ $I_C = 10\text{ A}$ $V_{CE} = 4\text{ V}$	1000 500			
$t_{on}$ $t_{off}$	Resistive load Turn-on time Turn-off time	$I_C = 10\text{ A}$ $R_L = 3\ \Omega$ $I_{B1} = -I_{B2} = 40\text{ mA}$		0.9 4		$\mu\text{s}$ $\mu\text{s}$

1. Pulse test: pulse duration  $\leq 300\ \mu\text{s}$ , duty cycle  $\leq 2\%$ .



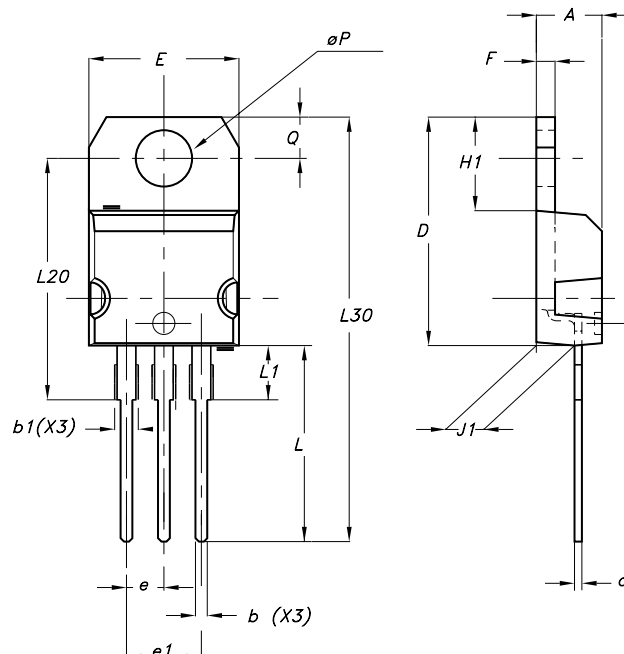
### Resistive load switching test circuit



1. Fast electronic switch
2. Non-inductive resistor



## Package Information TO-220S



DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A	4.40		4.60	0.173		0.181
b	0.61		0.88	0.024		0.034
b1	1.15		1.70	0.045		0.066
c	0.49		0.70	0.019		0.027
D	15.25		15.75	0.60		0.620
E	10		10.40	0.393		0.409
e	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
F	1.23		1.32	0.048		0.052
H1	6.20		6.60	0.244		0.256
J1	2.40		2.72	0.094		0.107
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L20		16.40			0.645	
L30		28.90			1.137	
øP	3.75		3.85	0.147		0.151
Q	2.65		2.95	0.104		0.116



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